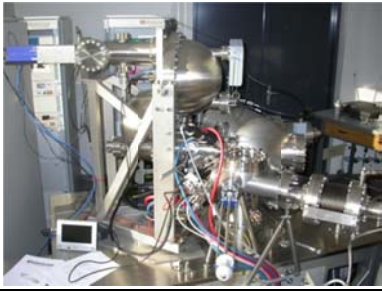



Characterisation

Omicron MXPS, Omicron XPEEM

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Material class:	Silicon X	Polymer X	Metal X	Ceramic	Glass	Organic x	Other
Short technology description:	MXPS is a high resolution, high performance spectrometer equipped with mono-chromatic X-Ray sources and He (I and II) UV lamp, charge neutralisation, ion gun, and in-situ polarization. Preparation chamber allows resistive heating of the sample up to 800°C and electron-gun heating up to 2000°C. XPEEM is a state-of-the-art spectrometer allowing realise XPS imaging with sub micrometer spatial resolution. Preparation chamber allows resistive heating of the sample up to 800°C and electron-gun heating up to 2000°C.						
Typical structures and designs:				XPEEM tool			
				MXPS tool			
Special features:	– Study of electronic structures, sub-micrometric XPS						
Limitations, constraints:	– low typography, highly insulating materials						
Material examples:	– Si-based nanoobjects, metal nano deposits, nano catalysts, SAMS etc						